

May 2001

FQP13N06L

60V LOGIC N-Channel MOSFET

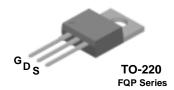
General Description

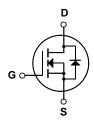
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 13.6A, 60V, $R_{DS(on)}$ = 0.11 Ω @V_{GS} = 10 V Low gate charge (typical 4.8 nC)
- Low Crss (typical 17 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP13N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°	°C)	13.6	Α
	- Continuous (T _C = 100°C)		9.6	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	54.4	Α
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	90	mJ
I _{AR}	Avalanche Current	(Note 1)	13.6	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P _D	Power Dissipation (T _C = 25°C)		45	W
	- Derate above 25°C		0.3	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.35	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.05		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 150°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics			,		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.5	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 6.8 A		0.088	0.11	
' DS(on)	On-Resistance	V _{GS} =5 V, I _D =6.8 A			0.14	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 25 V, I _D = 6.8 A (Note 4)		7		S
Dynami	ic Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		270	350	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		95	125	pF
C _{rss}	Reverse Transfer Capacitance			17	23	pF
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V 20 V I 6 8 A		8	25	ns
t _r	Turn-On Rise Time	$V_{DD} = 30 \text{ V}, I_{D} = 6.8 \text{ A},$		90	190	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$		20	50	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		40	90	ns
Q _g	Total Gate Charge	V _{DS} = 48 V, I _D = 13.6 A,		4.8	6.4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$		1.6		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		2.7		nC
	Source Diode Characteristics a				40.0	
I _S	Maximum Continuous Drain-Source Diode Forward Current				13.6	A
I _{SM}	Maximum Pulsed Drain-Source Diode F				54.4	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 13.6 A			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 13.6 \text{ A,}$		45		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		45		nC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 570μ H, I $_{AS}$ = 13.6A, V $_{DD}$ = 25V, R $_{G}$ = $25~\Omega$, Starting T $_{J}$ = 25° C 3. I $_{SD}$ $\leq 13.6A$, di/dt ≤ 300 A/ μ s, V $_{DD}$ $\leq BV_{DSS}$, Starting T $_{J}$ = 25° C 4. Pulse Test : Pulse width $\leq 300\mu$ s, Duty cycle $\leq 2\%$ 5. Essentially independent of operating temperature

Typical Characteristics

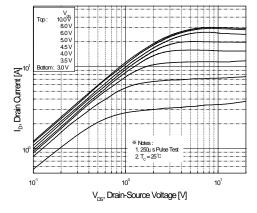


Figure 1. On-Region Characteristics

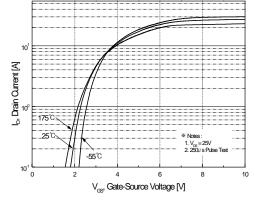


Figure 2. Transfer Characteristics

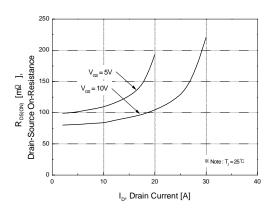


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

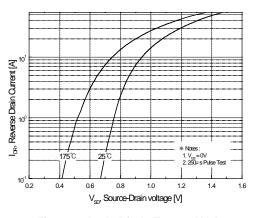


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

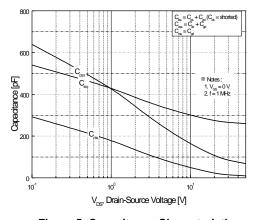


Figure 5. Capacitance Characteristics

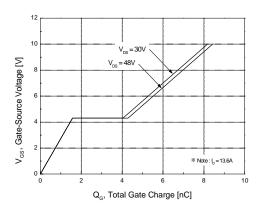
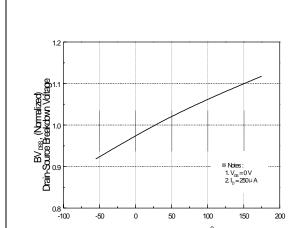


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

T,, Junction Temperature [°C]

150

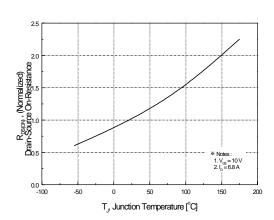


Figure 8. On-Resistance Variation vs. Temperature

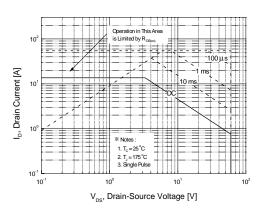


Figure 9. Maximum Safe Operating Area

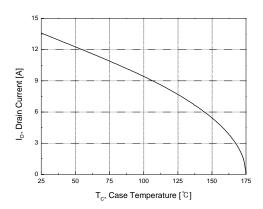


Figure 10. Maximum Drain Current vs. Case Temperature

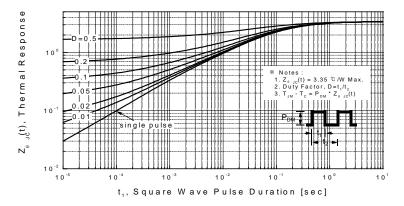
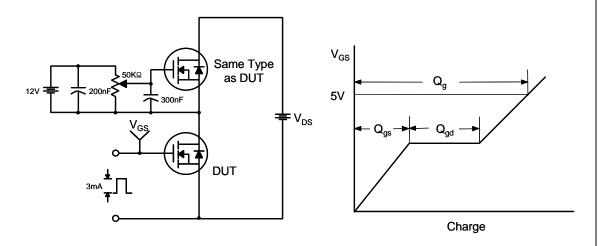


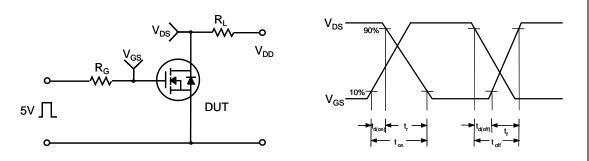
Figure 11. Transient Thermal Response Curve

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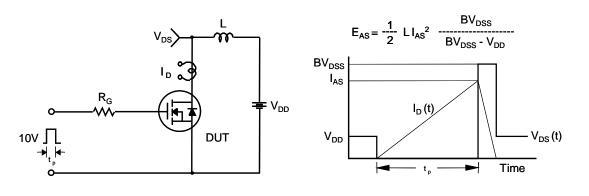
Gate Charge Test Circuit & Waveform



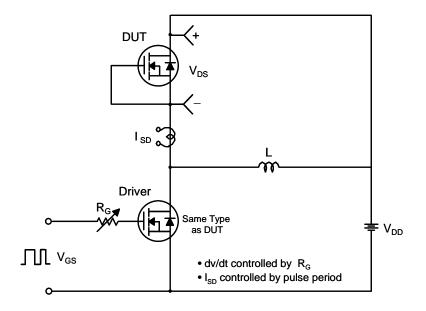
Resistive Switching Test Circuit & Waveforms



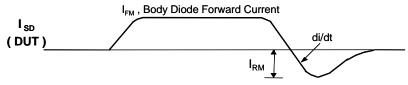
Unclamped Inductive Switching Test Circuit & Waveforms



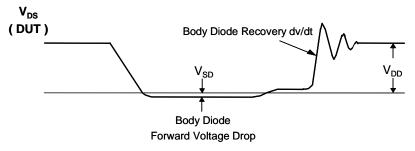
Peak Diode Recovery dv/dt Test Circuit & Waveforms

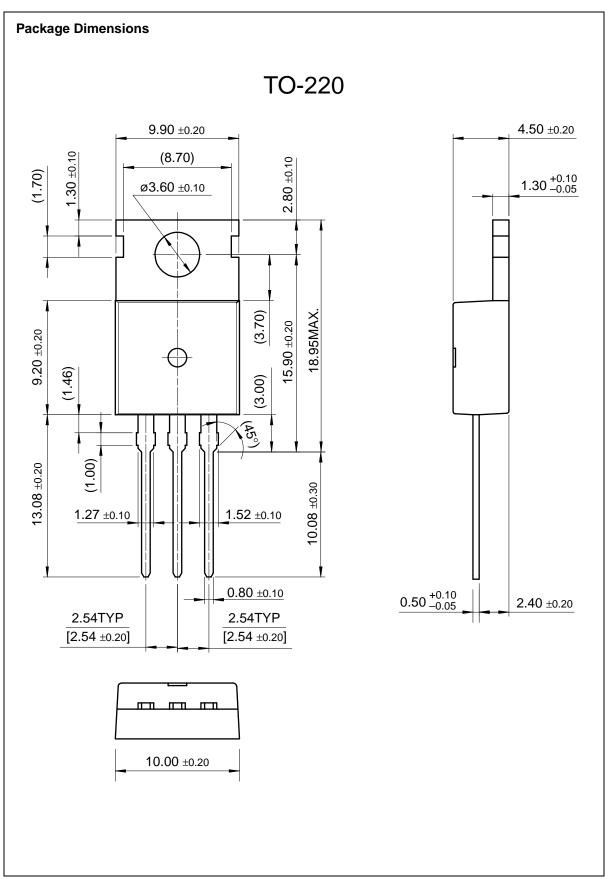






Body Diode Reverse Current





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